Notice of References Cited Application/Control No. 10/568,947 Examiner Hai H. Huynh Applicant(s)/Patent Under Reexamination MUTO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,051,709 B1	05-2006	Muto et al.	123/399
	В	US-			
	O	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	К	US-			
51	L	US-	- 1		
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q			·		
	R				·	
	S					
	Т					

NON-PATENT DOCUMENTS

	-	
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	ט	
	>	
	8	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.